

Supplementary Information.

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Supplementary Information.

Changing thresholds

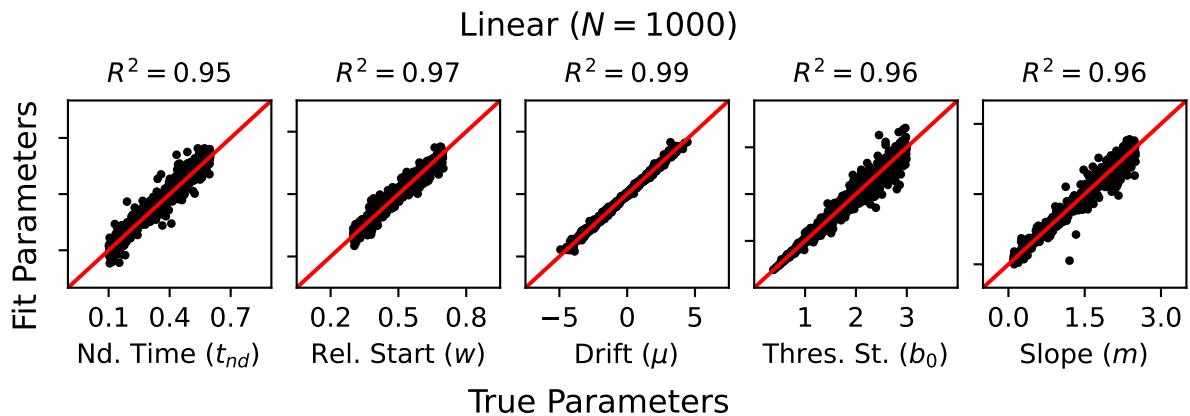


Figure 1. Quality of fit for the linear CT for $N = 1,000$ simulated data points.

Horizontal axes indicate the true simulated parameter values, while the vertical axes indicate the parameter values which best fit the simulated data. The red lines on each scatter plot denote the location where the simulation and fit parameters are equal. The correlation coefficients R^2 above each panel indicate the quality of fit to the red line.

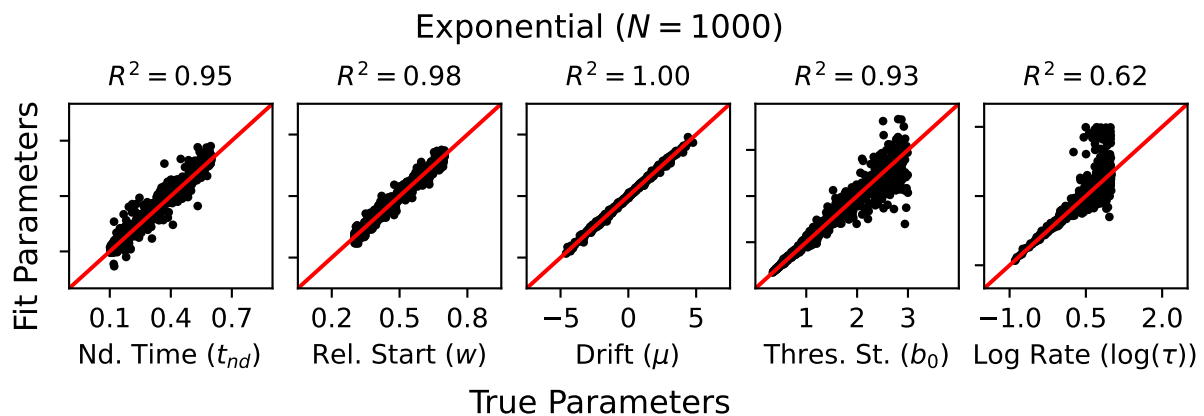


Figure 2. Quality of fit for the exponential CT for $N = 1,000$ simulated data points.

Horizontal axes indicate the true simulated parameter values, while the vertical axes indicate the parameter values which best fit the simulated data. The red lines on each scatter plot denote the location where the simulation and fit parameters are equal. The correlation coefficients R^2 above each panel indicate the quality of fit to the red line.

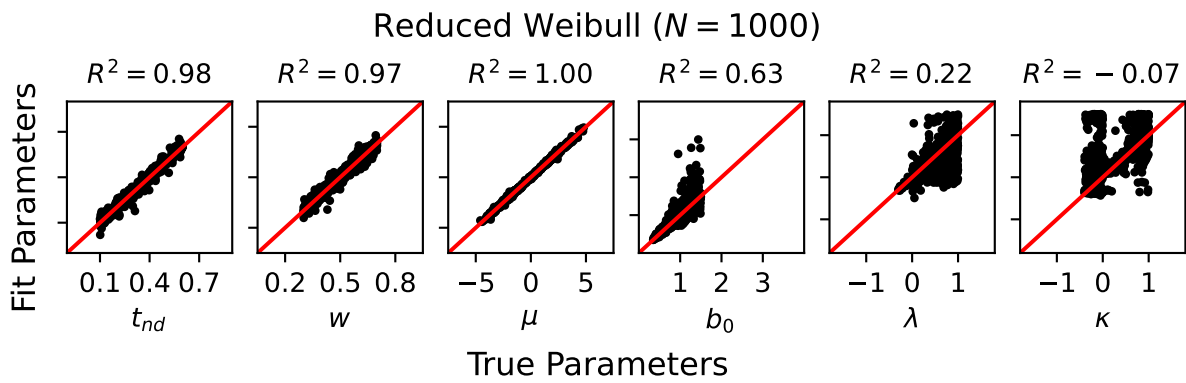


Figure 3. Quality of fit for the exponential CT for $N = 1,000$ simulated data points. Horizontal axes indicate the true simulated parameter values, while the vertical axes indicate the parameter values which best fit the simulated data. The red lines on each scatter plot denote the location where the simulation and fit parameters are equal. The correlation coefficients R^2 above each panel indicate the quality of fit to the red line.